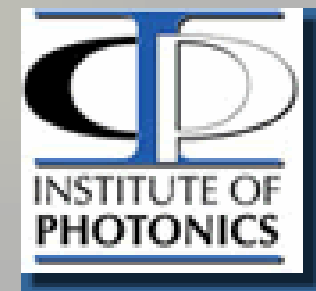


Lithographic Processing of Photonic Crystal Structures on GaN Epilayers for LED Applications

Ali Z. Khokhar¹, Douglas S. MacIntyre¹, Faiz Rahman¹, Nigel P. Johnson¹, Ian M. Watson², Erdan Gu², Haoxiang Zhang², Martin D. Dawson² and Richard M. De La Rue¹

¹Department of Electronics and Electrical Engineering, University of Glasgow
Rankine Building, Oakfield Avenue
Glasgow G12 8LT United Kingdom

²Institute of Photonics, University of Strathclyde
Wolfson Centre, 106 Rottenrow
Glasgow G4 0NW United Kingdom



Photonic Quasicrystal LEDs for Display Illumination (PQLDI)

Project Objective:

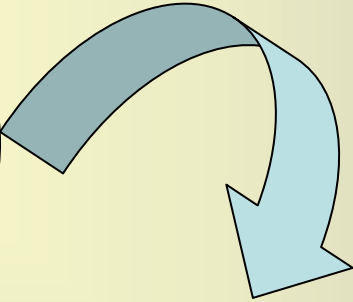
Demonstrate High Brightness LEDs Suitable for Backlighting Large Screen LCD Televisions.

Devices must satisfy the following criteria:

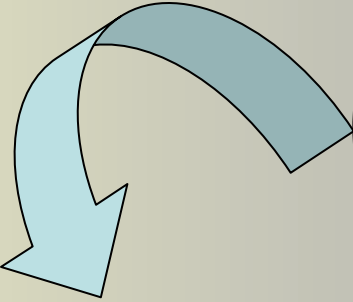
- 1) Sufficient brightness in a small form factor
- 2) Appropriate radial intensity distribution
- 3) Provision of the right colour point



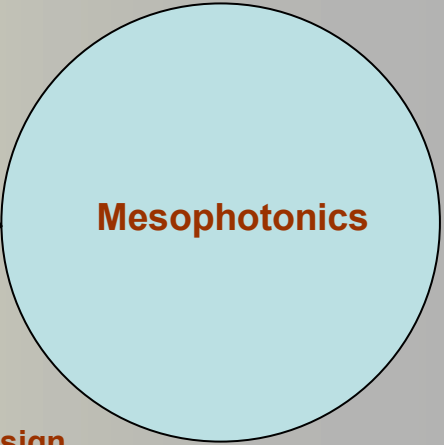
**Sharp
Laboratories
of Europe**



**Device Simulation
Material
System Integration**



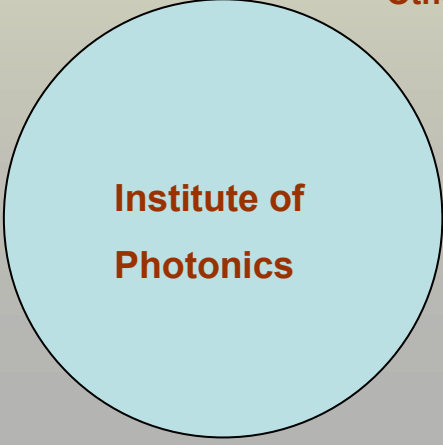
**Photonic Quasicrystal Design
Material**



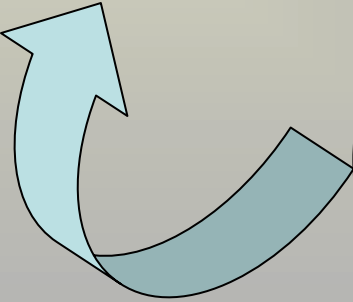
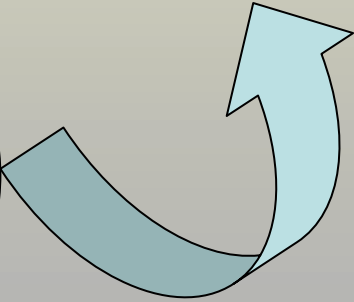
Mesophotonics

**Device Fabrication:
Dry Etching
Other Steps**

**Device Fabrication:
E-beam Lithography
Nano-imprint Lithography**



**Institute of
Photonics**



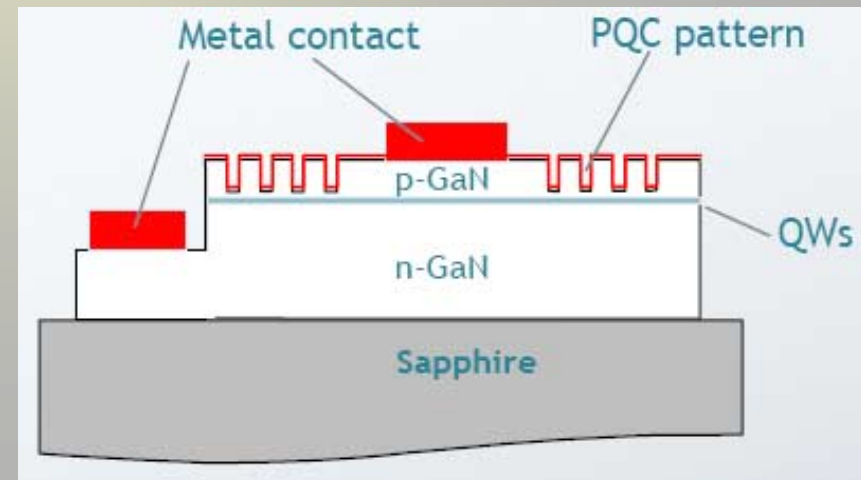
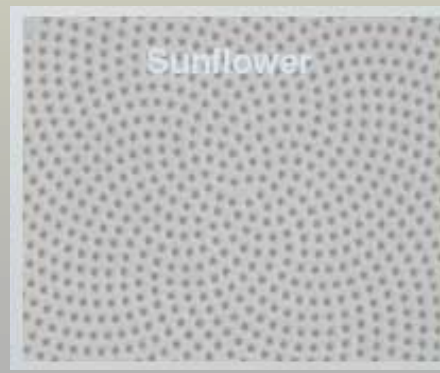
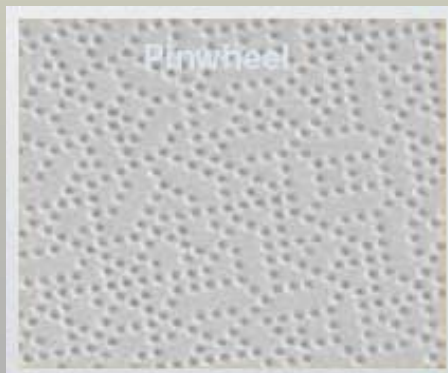
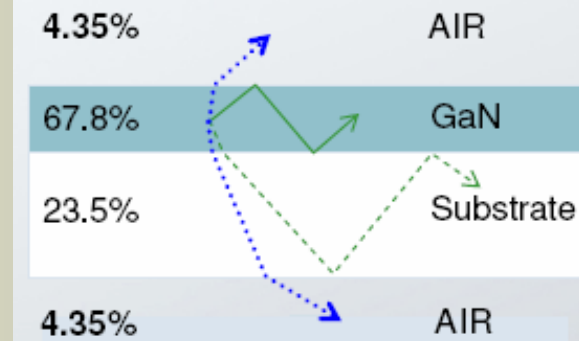
**University of
Glasgow**

Photonic Quasicrystal-based Light Extraction

Courtesy: Mesophotonics Ltd.

- 2 Fundamental problems of LEDs
 - Limited conversion of electrical to optical energy
 - Large % of Emitted light trapped inside high index GaN layer.
- Photonic crystals
 - Provide optimal leakage mechanism for light trapped in high index layers.
 - Improves extraction efficiency.
 - Increase efficiency of light emission
 - Potentially $\eta_{\text{rad}} \cdot \eta_{\text{extr}} > 75\%$

Percentage light trapped in each layer

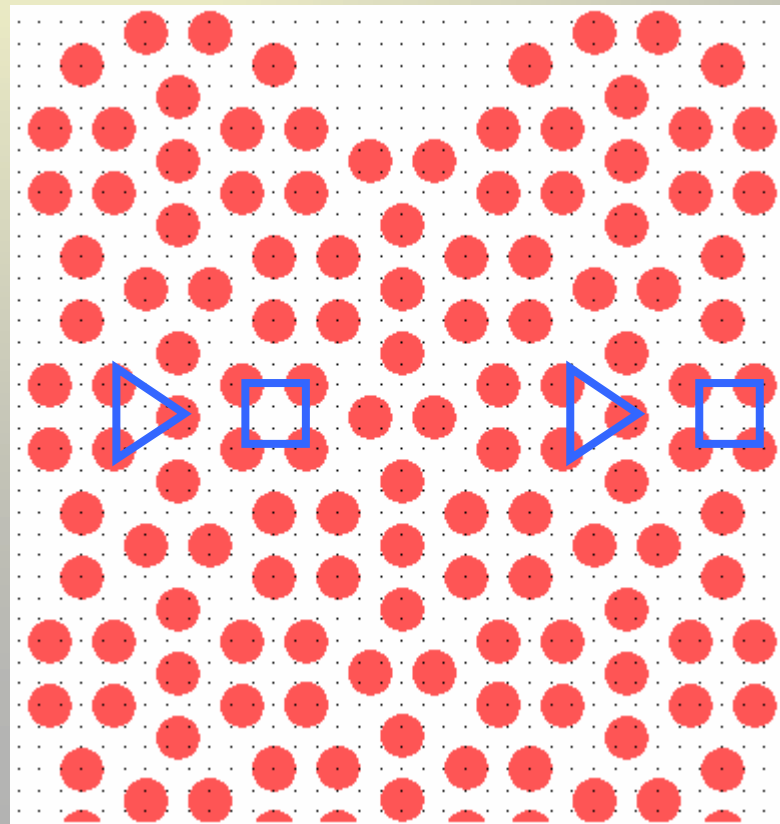


Fabrication of Photonic Quasicrystals through E-beam Lithography Techniques

- VB6 machine
 - *High resolution e-beam lithography tool: spot size 3 nm*
 - *Capable of writing 10 nm lines*
- Resists tested
 - *HSQ, PMMA, ZEP, UV-III*
- Dose tests
 - *100 KV at 350 – 1600 $\mu\text{C}/\text{cm}^2$*
- Different substrates
 - Si
 - *for process and tool calibration*
 - Quartz
 - *Stamp for nano-imprinting via UV curing polymer*
 - GaN
 - *final substrate for LEDs*

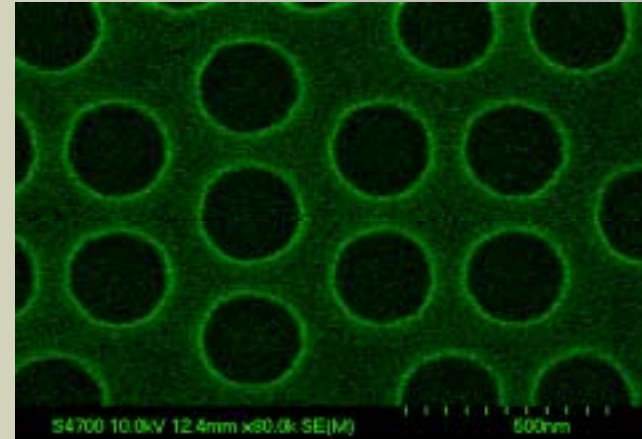
12-fold PhQC pattern (University of Glasgow)

- Square + Triangular lattice
- Hole diameter 200 nm
- Pattern 300 x 300 μm

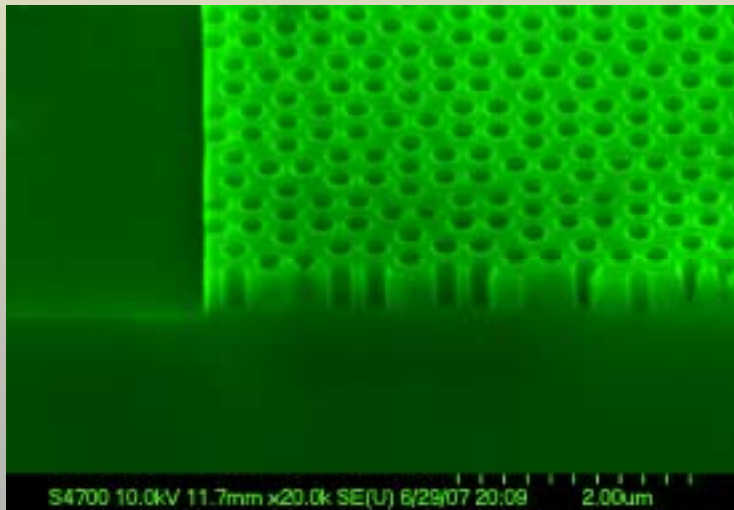


Pattern Transfer to Si Substrate

- 12-fold Quasi PhC
 - Square + Triangular lattice
- Mask
 - Hydrogen Silsesquioxane (HSQ)
 - High resolution negative tone e-beam resist
 - @ 3000 RPM : thickness 200 nm



Pattern transfer to HSQ

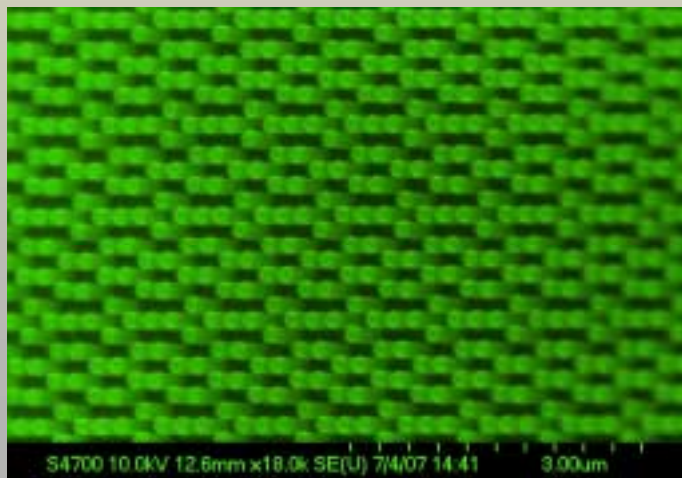
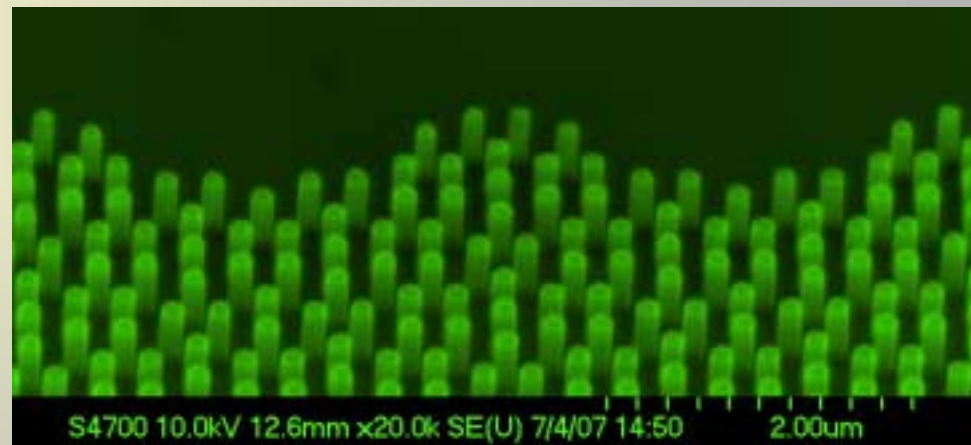


Pattern transfer to Si after dry-etching

- Dry-etching recipe:
- ICP ; SF_6 / C_4F_8
- 220 nm etch depth

Inverse Pattern on Si substrate

- Could act as a stamp for nano-imprinting
- Inverse pattern of Quasi PhC

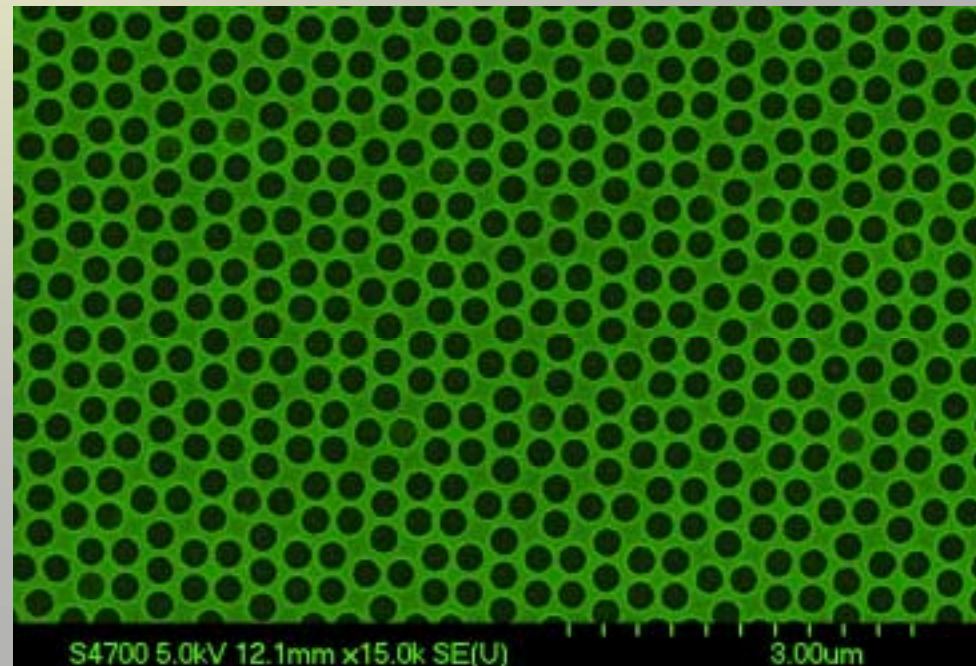


- Dry-etching recipe:
- ICP ; SF_6 / C_4F_8
- *220 nm etching depth*

Patterning on PMMA resist

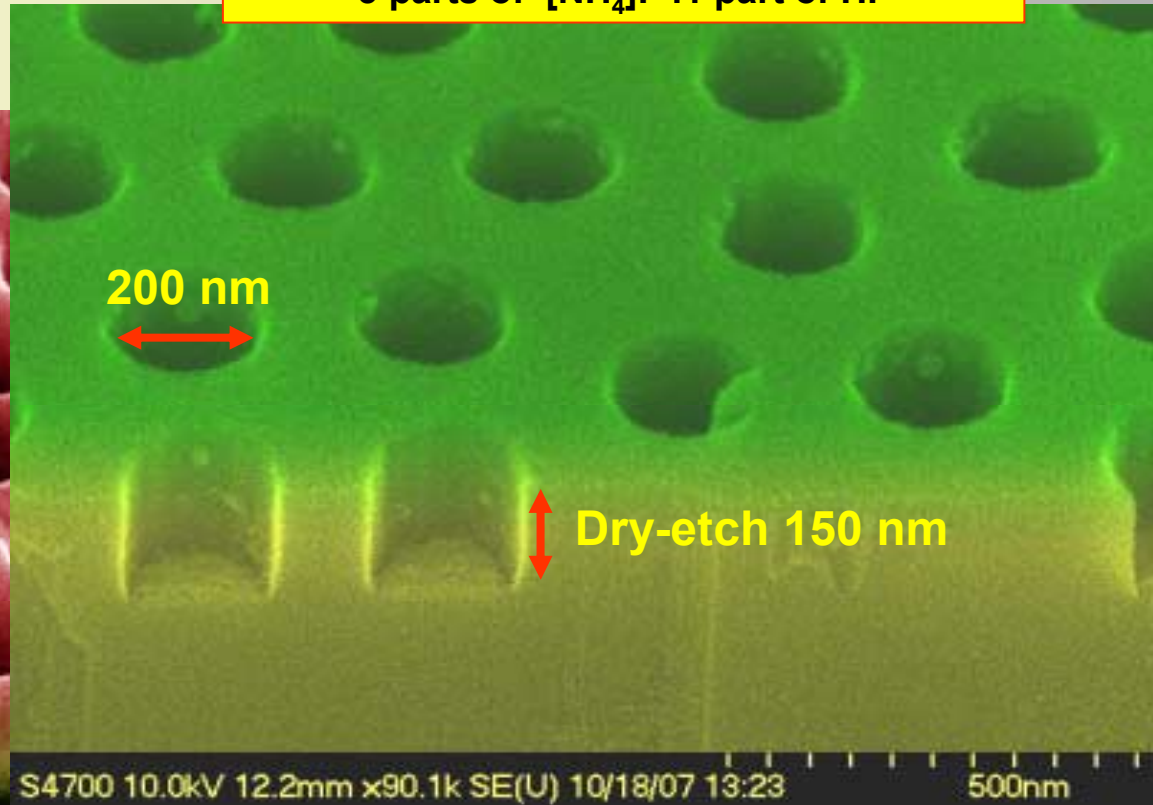
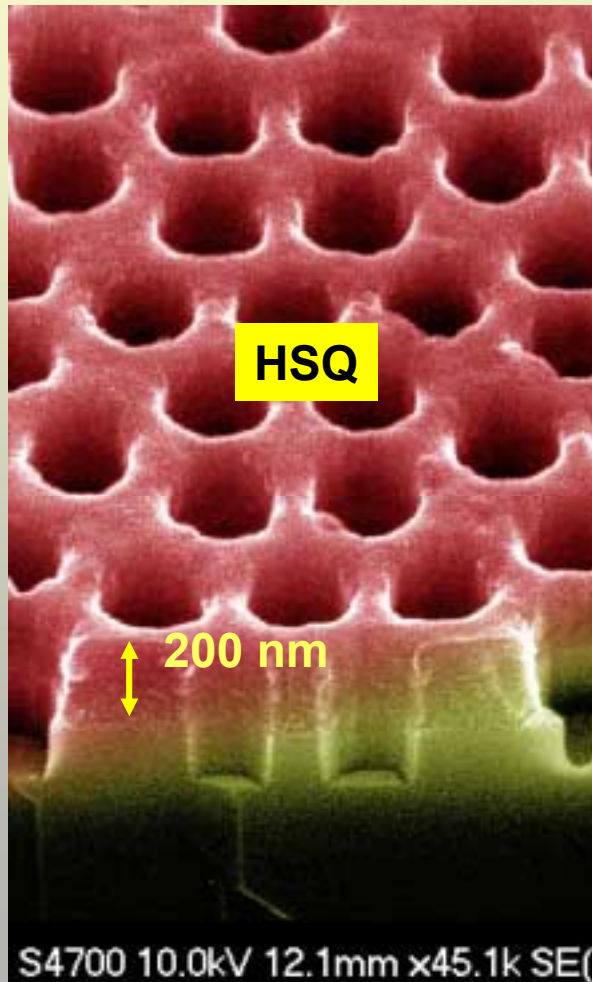
- Quartz substrate
- For nano-imprinting via UV curing polymer
- PMMA (Polymethyl Methacrylate)
 - *Positive tone e-beam resist*
 - *double layer PMMA @ 5000 RPM*
 - *Final thickness 200 nm*

Pattern transfer to PMMA



Before and After Stripping HSQ Mask

After (5:1) HF
5 parts of $[\text{NH}_4]\text{F}$: 1 part of HF



Before and After Stripping HSQ Mask

After (5:1) HF
5 parts of $[\text{NH}_4]\text{F}$: 1 part of HF

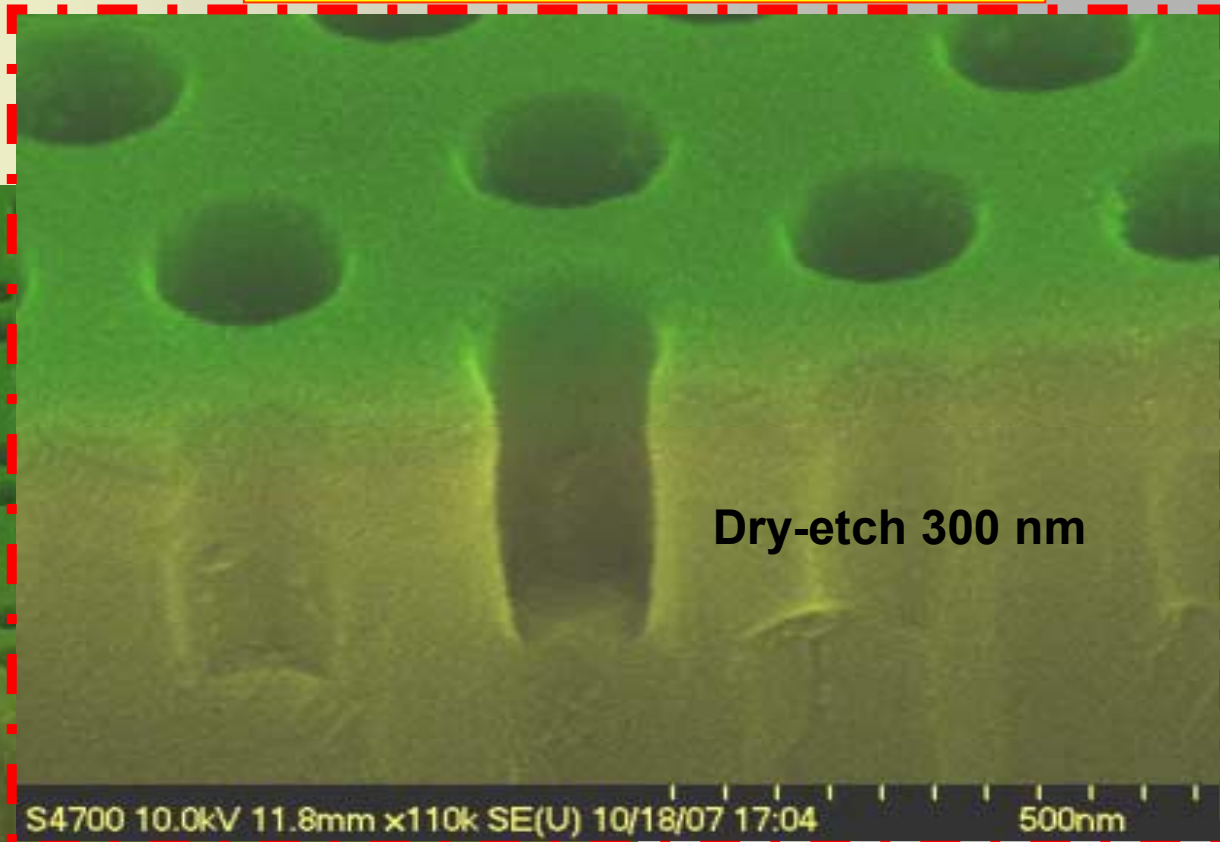
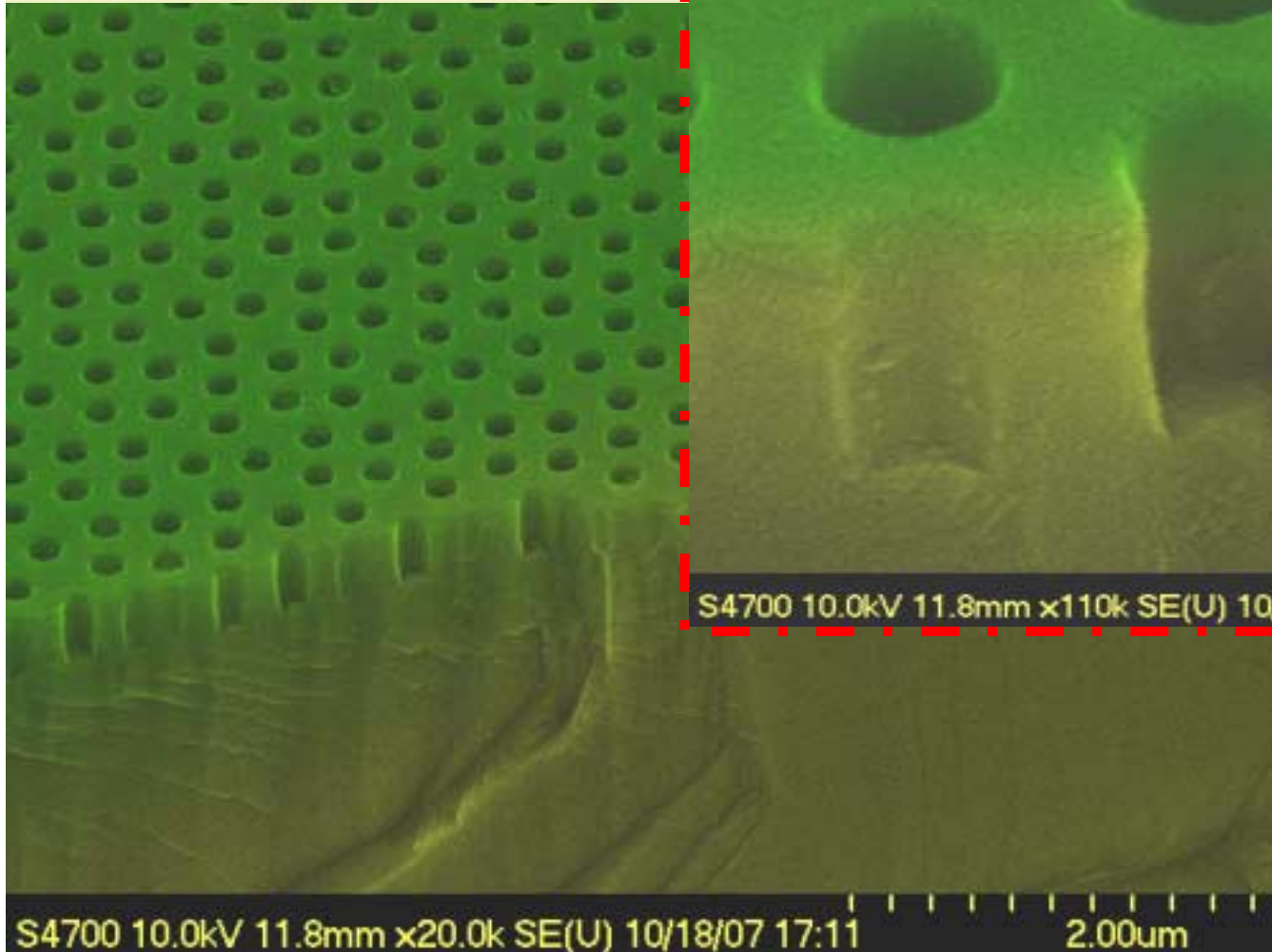
Dry-etch 300 nm

S4700 10.0kV 11.8mm x110k SE(U) 10/18/07 17:04

500nm

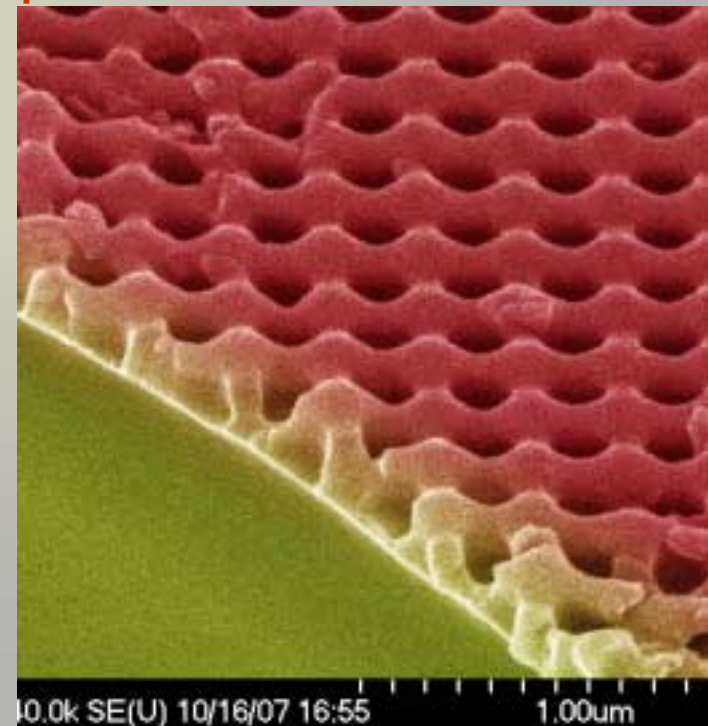
S4700 10.0kV 11.8mm x20.0k SE(U) 10/18/07 17:11

2.00um



Nano-imprinting on GaN

- Ormoclear
 - Hybrid inorganic polymer
 - (4:1) 4 parts of thinner : 1 part of ormoclear
 - Spin @ 4000 RPM
 - Pre-baked at 80 °C for 2 minutes
 - Pressure upto 1 Tonne by using hydraulic press on area of 64 mm² (153 MPa)
 - Thickness ~ 200 – 250 nm
 - UV curing for 3 minute
 - By using Mask Aligner $\lambda = 365$ nm
 - Post-baked at 180 °C for 1 – 2 hours.
 - Residual layer < 20 nm



SUMMARY

The PQLDI project has demonstrated high quality, largely defect-free patterning of PhQC light extraction structures on GaN

Similar results have been obtained with both direct write E-beam lithography and with flat stamp nano-imprint lithography

Next we shall work on fabricating complete diodes, their electrical and optical characterisation and on demonstrating roll nano-imprinting of PhQC structures